

## ECE/CS 5720/6720

### Assignment for Week 4

1. Read Sections 3.1-3.8, 3.11 in Johns & Martin. Work problems 3.1, 3.2, 3.3, 3.5, 3.6, and 3.11 (5 points each). Note: In problem 3.5, assume that the circuit is begin driven by an identical common-source circuit. In other words, assume that  $R_{in}$  equals  $R_{out}$  ( $R_2$ ).
  - Before continuing with problems 2 and 3 in this problem set, work through the MATLAB curve fitting exercise. (Do not turn in the results of this exercise.)
2. (10 points)  $I_D$  vs.  $V_{GS}$ . Load the MATLAB dataset `vgssweep.dat` from the class web page. This  $81 \times 2$  matrix contains  $I$ - $V$  data taken from a  $3.6\mu\text{m} \times 3.6\mu\text{m}$   $n$ MOS transistor fabricated in a  $1.2\mu\text{m}$  CMOS process. The gate-to-source voltage (column 1, units = V) was swept from zero to 1.0V while the drain current (column 2, units = A) was measured with a sensitive ammeter. The ammeter was capable of measuring currents as small as 3pA. Below this level, the current readings are not accurate. Measurements were taken with  $V_{SB} = 0$ . The drain-to-source voltage was held constant at 1.0V during the measurement. Turn in the following:
  - a. A linear-axis plot of  $I_D$  vs.  $V_{GS}$  with a fit to the square-law behavior characteristic of above-threshold MOSFETs. *In all plots in Problems 2 and 3, plot measured data points as circles and your theoretical fit as a continuous line.* You may use any method (including trial-and-error by hand) to find parameters that result in a good fit. Label your axes and indicate the threshold voltage and a value for  $\mu_n C_{ox}'/2$  (based on your fit). Given the gate oxide thickness of  $305\text{\AA}$ , what is the electron mobility  $\mu_n$  in this process (in units of  $\text{cm}^2/\text{V}\cdot\text{s}$ )?
  - b. A plot of the square root of drain current (i.e.,  $I_D^{1/2}$ ) vs.  $V_{GS}$  with a fit to the square-law behavior characteristic of above-threshold MOSFETs. You should use `polyfit` to fit the straight-line (above threshold) portion of this plot. The x-intercept point will be your threshold voltage. Label your axes and mark the threshold voltage (based on your fit). What is the drain current at  $V_{GS} = V_m$ ?
  - c. The transconductance  $g_m$  is given by  $\partial I_D / \partial V_{GS}$ , but we can approximate it as  $\Delta I_D / \Delta V_{GS}$  for small increments in gate voltage. Plot the transconductance vs. gate voltage from the data given. The `diff` command in MATLAB (type “`help diff`”) is useful for this type of analysis.

- d. Plot the **normalized transconductance**  $g_m/I_D$  (linear scale) vs. gate voltage (linear scale). What is the maximum value of this parameter (with units!), and in which region is it found?

**Note:** For all fits, fit only the appropriate regions!

3. (10 points)  **$I_D$  vs.  $V_{DS}$** . Load the MATLAB dataset `vdssweep.dat` from the class web page. This  $81 \times 2$  matrix contains  $I$ - $V$  taken from a  $3.6\mu\text{m} \times 3.6\mu\text{m}$   $n$ MOS transistor fabricated in a  $1.2\mu\text{m}$  CMOS process. The drain-to-source voltage (column 1, units = V) was swept from zero to 5.0V while the drain current (column 2, units = A) was measured. The gate-to-source voltage was held constant during the measurement, and was quite low so that the transistor enters active (saturation) region for very small values of  $V_{DS}$ . Measurements were taken with  $V_{SB} = 0$ . Turn in the following:
  - a. A linear plot of  $I_D$  vs.  $V_{DS}$  with a linear fit to the saturation region (use `polyfit` over the appropriate range). Label your axes and indicate the Early voltage  $V_A$  (based on your fit). What is the value of  $\lambda$ ? What is the output resistance  $r_{ds}$ ?
  - b. Using techniques outlined in Problem 2c, plot the output resistance  $r_{ds}$  ( $\Delta V_{DS}/\Delta I_D$ ) vs.  $V_{DS}$  on a linear scale. Do the values of  $r_{ds}$  obtained here agree with the value derived from the fit in part (a)?